

### **5.5A, 200V, 0.400 Ohm, N-Channel Power MOSFET**

The 2N6798 is an N-Channel enhancement mode silicon gate power MOS field effect transistor designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. This type can be operated directly from integrated circuits.

Formerly developmental type TA\_\_\_\_\_.

### **Ordering Information**

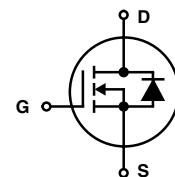
PART NUMBER	PACKAGE	BRAND
2N6798	TO-205AF	2N6798

NOTE: When ordering, include the entire part number.

### **Features**

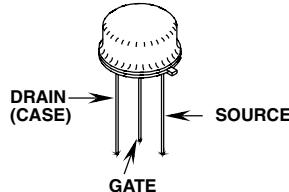
- 5.5A, 200V
- $r_{DS(ON)} = 0.400\Omega$
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Majority Carrier Device
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

### **Symbol**



### **Packaging**

**JEDEC TO-205AF**



**Absolute Maximum Ratings**  $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

		2N6798	UNITS
Drain to Source Voltage (Note 1) . . . . .	$V_{DS}$	200	V
Drain to Gate Voltage ( $R_{GS} = 20\text{k}\Omega$ ) (Note 1) . . . . .	$V_{DGR}$	200	V
Continuous Drain Current . . . . .	$I_D$	5.5	A
$T_C = 100^\circ\text{C}$ . . . . .	$I_D$	3.5	A
Pulsed Drain Current (Note 3) . . . . .	$I_{DM}$	22	A
Gate to Source Voltage . . . . .	$V_{GS}$	$\pm 20$	V
Continuous Source Current . . . . .	$I_S$	5.5	A
Pulse Source Current . . . . .	$I_{SM}$	22	A
Maximum Power Dissipation (Figure 1) . . . . .	$P_D$	25	W
Above $T_C = 25^\circ\text{C}$ , Derate Linearly (Figure 1) . . . . .		0.20	$\text{W}/^\circ\text{C}$
Operating and Storage Temperature . . . . .	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering			
Leads at 0.063in (1.6mm) from Case for 10s . . . . .	$T_L$	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	$T_{pkg}$	260	$^\circ\text{C}$

*CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.*

## NOTE:

1.  $T_J = 25^\circ\text{C}$  to  $125^\circ\text{C}$ .

**Electrical Specifications**  $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0\text{V}$ , $I_D = 0.25\text{mA}$	200	-	-	V
Gate Threshold Voltage	$V_{GS(\text{TH})}$	$V_{GS} = V_{DS}$ , $I_D = 0.5\text{mA}$	2.0	-	4.0	V
Gate to Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20\text{V}$ , $V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 200\text{V}$ , $V_{GS} = 0\text{V}$	-	-	250	$\mu\text{A}$
		$V_{DS} = 160\text{V}$ , $V_{GS} = 0\text{V}$ , $T_C = 125^\circ\text{C}$	-	-	1000	$\mu\text{A}$
On State Voltage (Note 2)	$V_{DS(\text{ON})}$	$V_{GS} = 10\text{V}$ , $I_D = 5.5\text{A}$	-	-	2.20	V
On Resistance (Note 2)	$r_{DS(\text{ON})}$	$V_{GS} = 10\text{V}$ , $I_D = 3.5\text{A}$ , $T_A = 25^\circ\text{C}$	-	0.25	0.400	$\Omega$
		$V_{GS} = 10\text{V}$ , $I_D = 3.5\text{A}$ , $T_A = 125^\circ\text{C}$	-	-	0.750	$\Omega$
Diode Forward Voltage (Note 2)	$V_{SD}$	$T_C = 25^\circ\text{C}$ , $I_S = 5.5\text{A}$ , $V_{GS} = 0\text{V}$	0.7	-	1.4	V
Forward Transconductance (Note 2)	$g_{fs}$	$V_{DS} = 5\text{V}$ , $I_D = 3.5\text{A}$	2.5	4.5	7.5	S
Input Capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1.0\text{MHz}$ (Figure 11)	350	600	900	pF
Output Capacitance	$C_{OSS}$		100	250	450	pF
Reverse Transfer Capacitance	$C_{RSS}$		40	80	150	pF
Turn-On Delay Time	$t_{d(\text{ON})}$	$V_{DD} \approx 77\text{V}$ , $I_D = 3.5\text{A}$ , $Z_O = 50\Omega$ , (Figure 15) MOSFET Switching Times are Essentially Independent of Operating Temperature.	-	-	30	ns
Rise Time	$t_r$		-	-	50	ns
Turn-Off Delay Time	$t_{d(\text{OFF})}$		-	-	50	ns
Fall Time	$t_f$		-	-	40	ns
Safe Operating Area	$\text{SOA}$	$V_{DS} = 160\text{V}$ , $I_D = 155\text{mA}$ (Figures 19, 20)	25	-	-	W
		$V_{DS} = 4.5\text{V}$ , $I_D = 5.5\text{A}$ (Figures 19, 20)	25	-	-	W
Thermal Resistance Junction to Case	$R_{\theta JC}$		-	-	5.0	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Free Air Operation	-	-	175	$^\circ\text{C}/\text{W}$

**Source to Drain Diode Specifications**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Reverse Recovery Time	$t_{rr}$	$T_J = 150^\circ\text{C}$ , $I_{SD} = 5.5\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	450	-	ns
Reverse Recovered Charge	$Q_{RR}$	$T_J = 150^\circ\text{C}$ , $I_{SD} = 5.5\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	3.0	-	$\mu\text{C}$

## NOTES:

2. Pulse test: pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .
3. Repetitive rating: pulse width limited by maximum junction temperature. See Transient Thermal impedance curve (Figure 3).

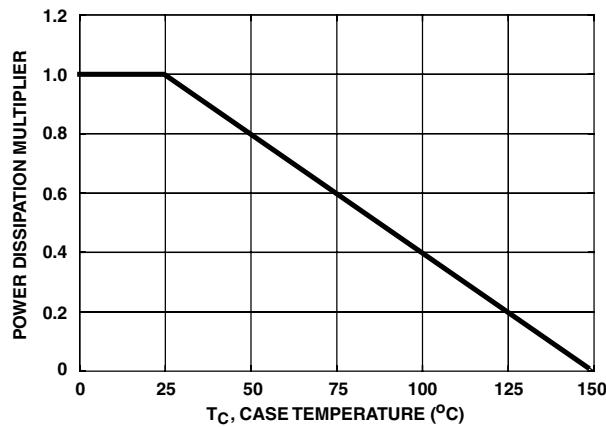
**Typical Performance Curves** Unless Otherwise Specified

FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

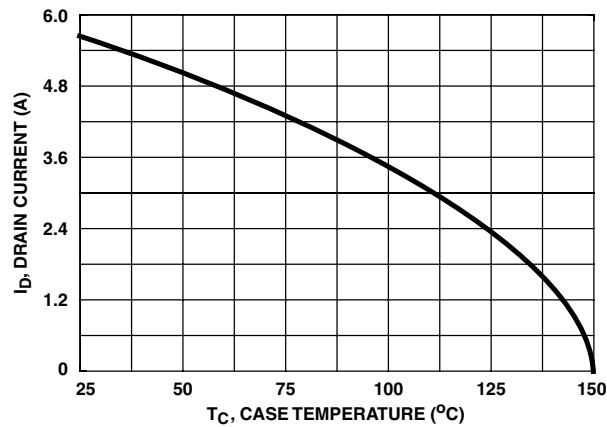


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

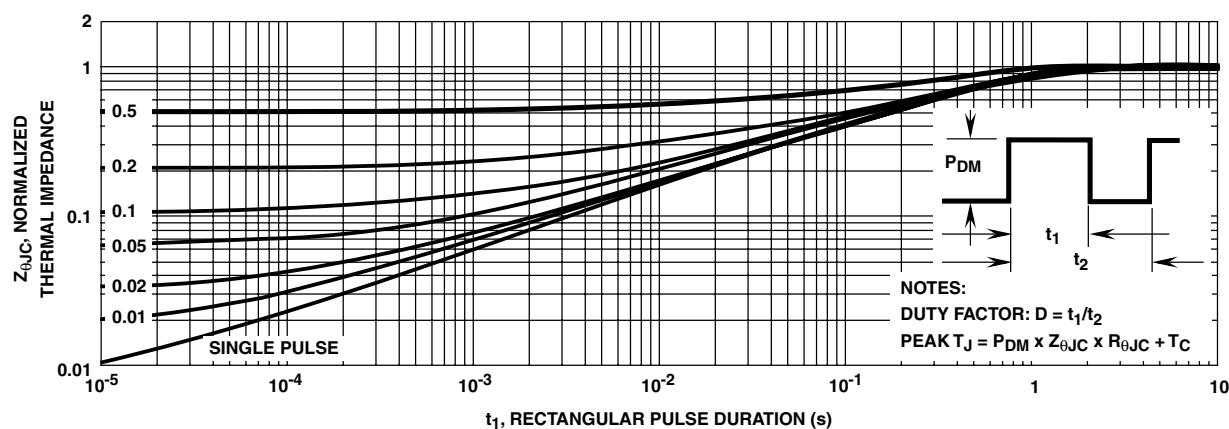


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

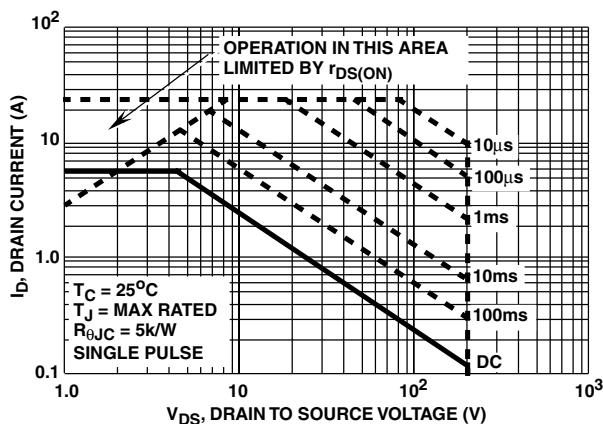


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

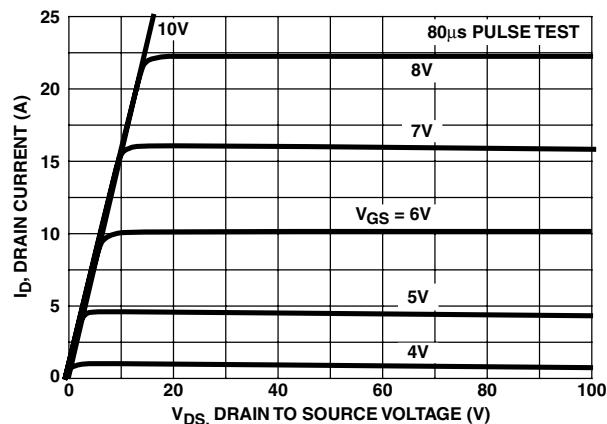


FIGURE 5. OUTPUT CHARACTERISTICS

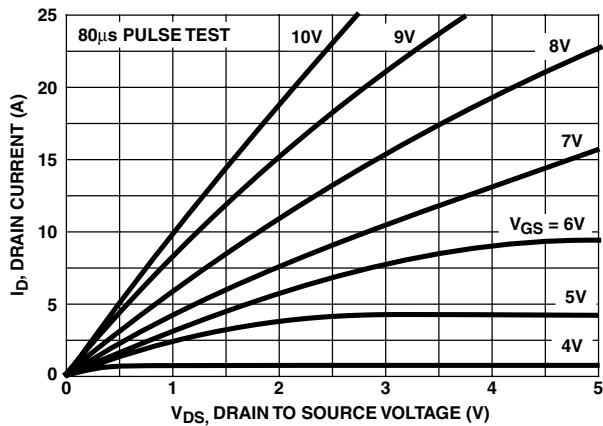
**Typical Performance Curves** Unless Otherwise Specified (Continued)

FIGURE 6. SATURATION CHARACTERISTICS

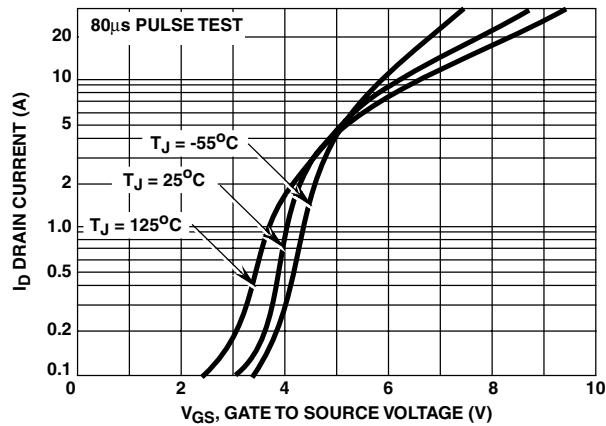


FIGURE 7. TYPICAL TRANSFER CHARACTERISTICS

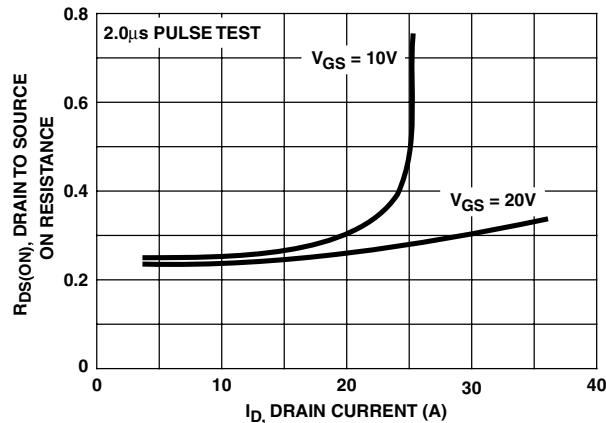


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

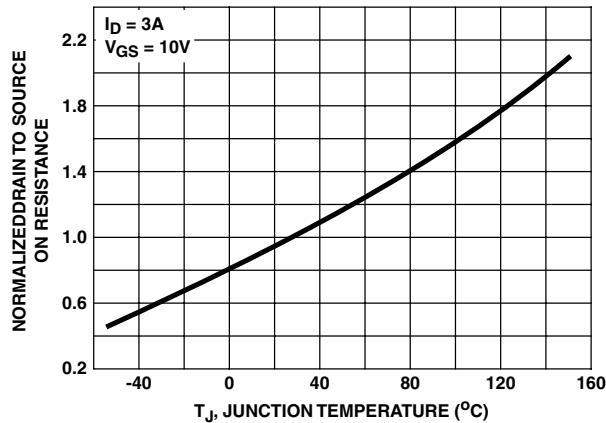


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

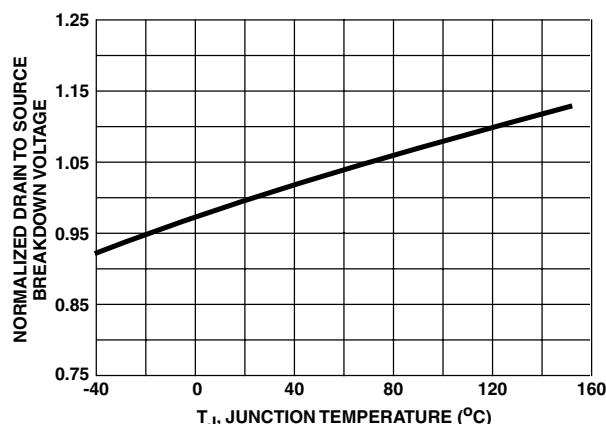


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

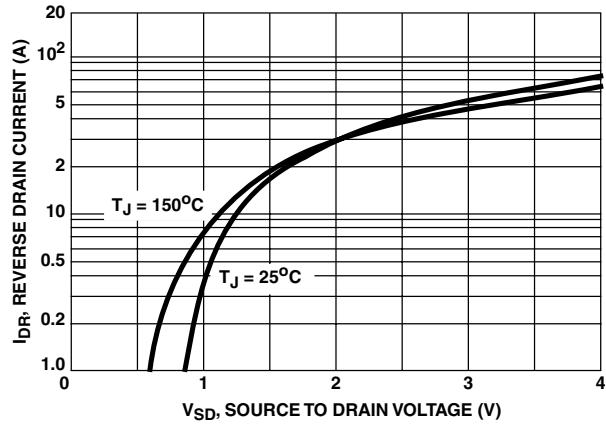


FIGURE 11. SOURCE TO DRAIN DIODE VOLTAGE

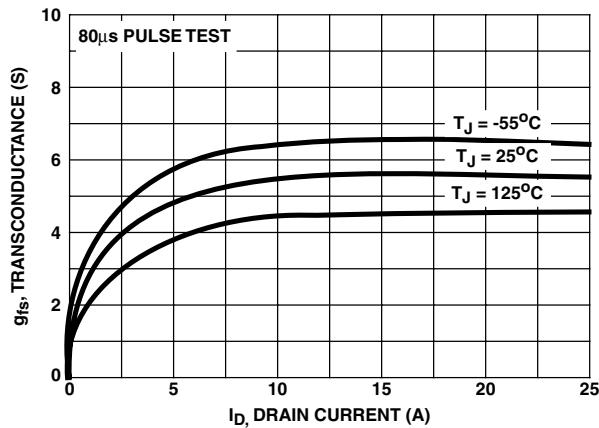
**Typical Performance Curves** Unless Otherwise Specified (Continued)

FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

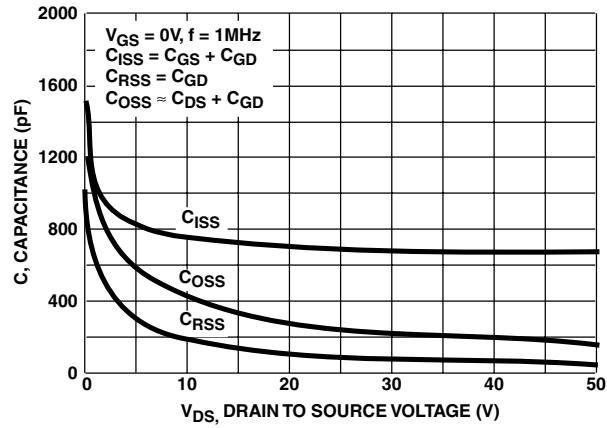


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

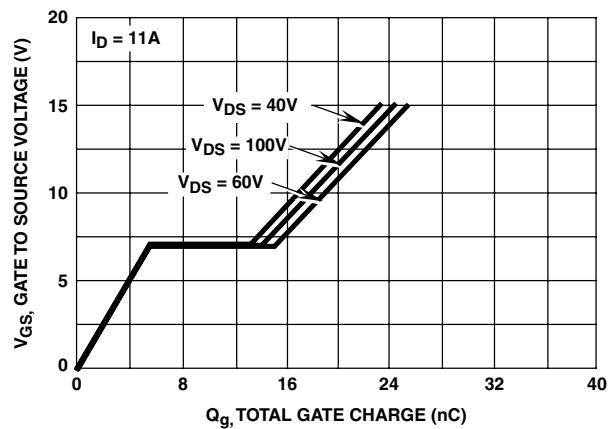


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

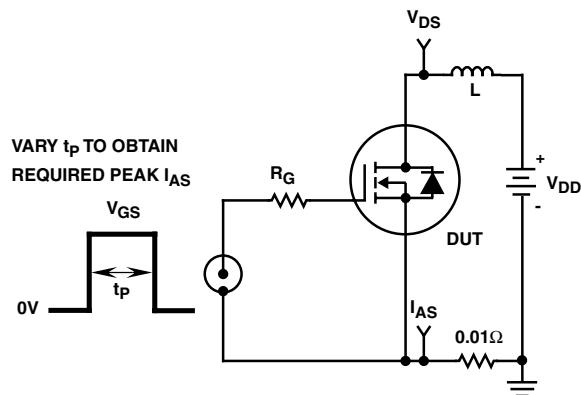
**Test Circuits and Waveforms**

FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

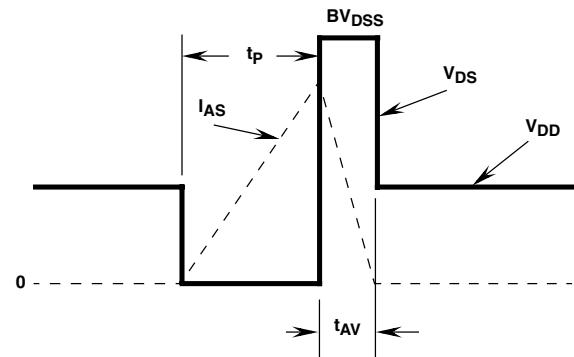


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

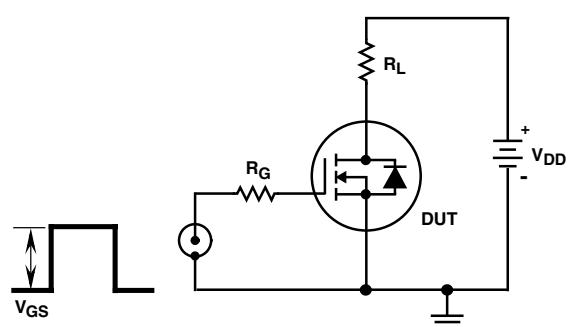


FIGURE 17. SWITCHING TIME TEST CIRCUIT

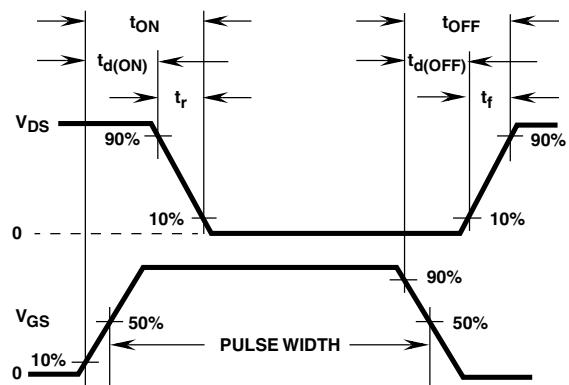


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

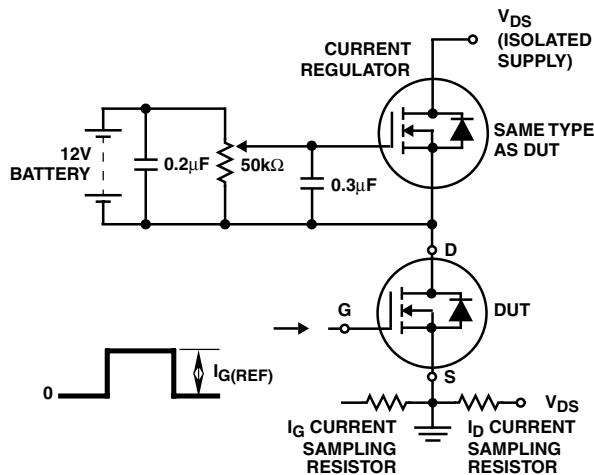


FIGURE 19. GATE CHARGE TEST CIRCUIT

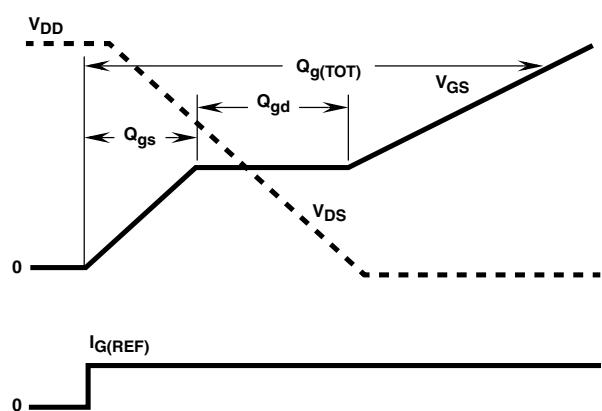


FIGURE 20. GATE CHARGE WAVEFORMS

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